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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPLN#	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10058787	01/30/2002	257	48	2822	DOLAN

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**CONTINUING DATA VERIFIED:

** FOREIGN APPLICATIONS VERIFIED:

JAPAN 2001-025227 02/01/2001

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed 35 USC 119 conditions met Verified and Acknowledged Examiners's initials		<input type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO ASAM.0038
TITLE : Semiconductor integrated circuit device, method of testing semiconductor integrated circuit device and method of manufacturing semiconductor integrated circuit device U.S. DEPT. OF COMM./PAT. & TM-PTO-436L(Rev. 12-94)			

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
Amount Due	Date Paid		Total Claims	Print Claim for O.G
ISSUE FEE		DRAWING		
		Sheets Drwg.	Figs.Drwg.	Print Fig.
TERMINAL		Primary Examiner		
DISCLAIMER		PREPARED FOR ISSUE Application Examiner		
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